

Search Notes**Application/Control No.**

10/664,500

Examiner

Maikhhanh Nguyen

Applicant(s)/Patent under Reexamination

YALOVSKY, MARK

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	530	5/5/2006	MK
715	517,519	5/5/2006	MK
715	520	5/5/2006	MK
707	100	5/5/2006	MK
Updated	above	11/15/2006	MK
Updated	above	6/13/2007	MK
Updated	above	1/17/2008	MK
715	200 228	1/17/2008	MK
715	234 244	1/17/2008	MK
715	245 246	1/17/2008	MK
715	251 253	1/17/2008	MK
715	255 256	1/17/2008	MK
715	273 856	1/17/2008	MK
715	857 858	1/17/2008	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
715	530	1/17/2008	MK
715	525	1/17/2008	MK
715	857	1/17/2008	MK
USPAT - USPGPub		1/17/2008	MK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	5/5/2006	MK
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/5/2006	MK
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	11/15/2006	MK
West Updated (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) See Search History Printout	6/13/2007	MK
Consulted with Primary William Bashore	1/14/2008	MK
West Updated (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout	1/17/2008	MK
Interference Search	1/17/2008	MK